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| Traveler Title | SNS PPU Tophat Leak Testing Traveler |
| Traveler Abstract | Traveler defines the leak testing process for the SNS PPU Tophats. |
| Traveler ID | SNSPPU-CM-LEAK-TPHT |
| Traveler Revision  | R1 |
| Traveler Author | Matt Marchlik |
| Traveler Date | 12-Mar-20 |
| NCR Informative Emails | edaly |
| NCR Dispositioners | marchlik,kwilson |
| D3 Emails | Marchlik,kwilson,edaly |
| Approval Names | M. Marchlik | K. M. Wilson | C. Wilcox | E.F. Daly |
| Approval Signatures |  |  |  |  |
| Approval Dates |  |  |  |  |
| Approval Title | Author | Reviewer |  | Project Manager |

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| References | List and Hyperlink all documents related to this traveler. This includes, but is not limited to: safety (THAs, SOPs, etc), drawings, procedures, and facility related documents. |
| [104110000-M8U-8200-A262](file:///X%3A%5CFacilities%5CSRF%20Institute%5C01%20-%20SRF%20Projects%5C01%20-%20Open%5C1.21.02.XXX%20-%20SNS%20PPU%20Design%20%26%20Construction%20of%207%20High%20Beta%20Cryomodules%20for%20ORNL%20-%20Ed%20Daly%5C06%20-%20Process%20Documents%5ETravelers%20%28SNSPPU%29%5CTravelers%20Included%20Files%20-%20XXXX%5CTPHT%5C104110000-M8U-8200-A262-R01.pdf) (TOPHAT WELDMENT) |  |  |  |  |
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| Revision Note |  |
| R1 | Initial release of this Traveler. |

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| Step No. | Instructions | Data Input |
| **General handling guidelines:** The tophats contain two o-ring grooves that must be protected during handling. Care shall be taken to not drop the tophats. The tophats should be handled according to standard cleaning and handling practices. |
| 1 | **Leak Check:** |
| Leak check the tophat per JLAB spec 11141-S-0033. Only tophats with serial numbers ending in 001, 014 and 028 require leak testing. Use the leak testing chamber provided by the tophat manufacturer. | [[TPHTSN]] <<TPHTSN>>[[LeakCheckTech]] <<SRF>>[[LeakCheckDate]] <<TIMESTAMP>>[[LeakcheckOk]] <<YESNO>>[[LeakcheckComment]] <<COMMENT>> |
| 2 | **Storage:** |
| Each tophat shall be re-packaged in it’s original protective packaging after leak testing. | [[StorageTech]] <<SRF>>[[StorageDate]] <<TIMESTAMP>> |